Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/841,666	TANAKA ET AL.	
Examiner	Art Unit	
HOAN C. NGUYEN	2871	

SEARCHED			
Class	Subclass	Date	Examiner
349	112	7/16/2007	CHN
362	333, 339	7/16/2007	CHN
428	172	7/16/2007	CHN
425	373-374	7/16/2007	CHN
156	462	7/16/2007	CHN
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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	es above and search	7/16/2007	CHN

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East search in US-PGPUB, USPAT, EPO, JPO, Derwent and IBM_TDB	7/16/2007	CHN		
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